Bilayer graphene electrooptic modulator with rib dielectric enhancing TE mode confinement

Figures

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Double-layer graphene on silicon has been proven to show high performance optical modulation [1] and has shown potential experimental possibilities [2]. We report a novel design of bilayer grapheneon-silicon electro-absorption modulator. Our design involves formation of a rib dielectric structure (SiO₂) within core silicon that pushes the mode towards top graphene layers. Dimensions of the dielectric rib can be h/2 and w/2, where h and w are height and width of core Si, respectively. Such the waveguide enhances TE mode confinement and improves light-graphene interaction. The TE and TM modal properties of the waveguide are studied using a Finite element method.

Our design significantly improves the TE mode confinement within graphene layers in a graphene-on-silicon rib waveguide configuration compared to that of a vertical air slot design [3]. This structure is possible to fabricate with existing SOI technology and has CMOS compatibility and on-chip integration.

References

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Figure 1: The TE Ex field profile. Waveguide parameters: Si width/height 0.6μ m/ 0.34μ m; bilayer graphene 0.69nm; buffer dielectric (Al₂O₃) 0.1μ m; rib dielectric (SiO₂) width/height 0.3μ m/ 0.17μ m.



Figure 2: Optical loss (TM, TE) as a function of Fermi level in waveguides with and without SiO2 dielectric rib. Refractive indices of Si, SiO₂ and Al₂O₃ were taken as 3.47, 2.09 and 3.02. In TM plot, a peak at μ = 0.507 eV denotes transition of graphene layer to metallic state, $\varepsilon_{graphene}$ = -0.0839+j0.5728, showing epsilon near zero effect in graphene.